

**1/3-inch Progressive Scan CCD Image Sensor with Square Pixel for B/W Cameras**

**Description**

The ICX084AL is a 1/3-inch interline CCD solid-state image sensor with a square pixel array which supports VGA format. Progressive scan allows all pixels signals to be output independently within approximately 1/30 second. This chip features an electronic shutter with variable charge-storage time which makes it possible to realize full-frame still image without a mechanical shutter. High sensitivity and low dark current are achieved through the adoption of HAD (Hole-Accumulation Diode) sensors.

This chip is suitable for applications such as two-dimensional bar code readers, PC input cameras, etc.

**Features**

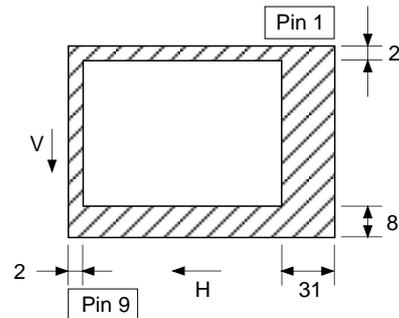
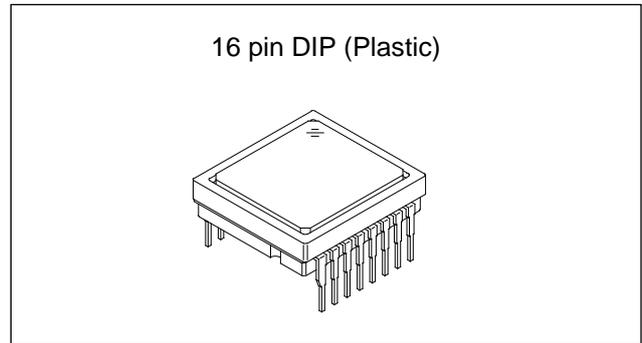
- Progressive scan allows individual readout of the image signals from all pixels.
- High vertical resolution (480 TV-lines) still image without a mechanical shutter.
- Square pixel unit cell
- Supports VGA format
- Horizontal drive frequency: 12.27MHz
- No voltage adjustments (reset gate and substrate bias are not adjusted.)
- High resolution, high sensitivity, low dark current
- Continuous variable-speed shutter  
1/30 (Typ.) to 1/10000s
- Low smear
- Excellent antiblooming characteristics
- Horizontal register: 5V drive
- 16-pin high precision plastic package (enables dual-surface standard)

**Device Structure**

- Interline CCD image sensor
- Optical size: 1/3-inch format
- Number of effective pixels: 659 (H) × 494 (V) approx. 330K pixels
- Total number of pixels: 692 (H) × 504 (V) approx. 350K pixels
- Chip size: 5.84mm (H) × 4.94mm (V)
- Unit cell size: 7.4µm (H) × 7.4µm (V)
- Optical black:
 

Horizontal (H) direction	Front 2 pixels, rear 31 pixels
Vertical (V) direction	Front 8 pixels, rear 2 pixels
- Number of dummy bits:
 

Horizontal	16
Vertical	5
- Substrate material: Silicon

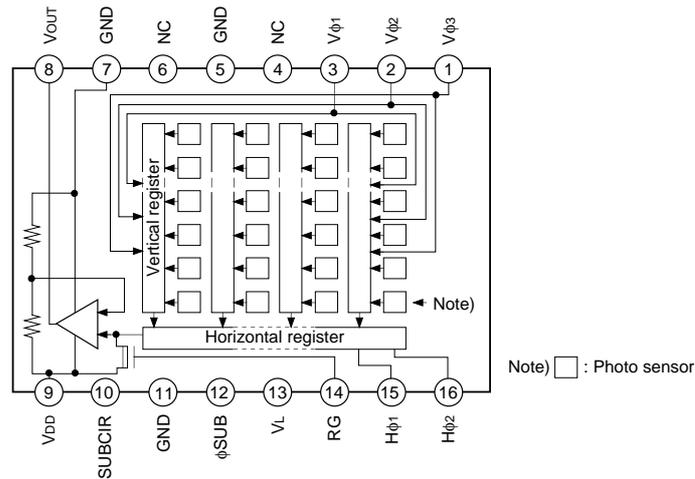


**Optical black position  
(Top View)**

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**Block Diagram and Pin Configuration**

(Top View)



**Pin Description**

Pin No.	Symbol	Description	Pin No.	Symbol	Description
1	$V\phi_3$	Vertical register transfer clock	9	$V_{DD}$	Supply voltage
2	$V\phi_2$	Vertical register transfer clock	10	SUBCIR	Supply voltage for the substrate voltage generation
3	$V\phi_1$	Vertical register transfer clock	11	GND	GND
4	NC		12	$\phi_{SUB}$	Substrate clock
5	GND	GND	13	$V_L$	Protective transistor bias
6	NC		14	RG	Reset gate clock
7	GND	GND	15	$H\phi_1$	Horizontal register transfer clock
8	$V_{OUT}$	Signal output	16	$H\phi_2$	Horizontal register transfer clock

**Absolute Maximum Ratings**

Item		Ratings	Unit	Remarks
Substrate clock $\phi_{SUB} - GND$		-0.3 to +36	V	
Supply voltage	$V_{DD}, V_{OUT}, SUBCIR - GND$	-0.3 to +18	V	
	$V_{DD}, V_{OUT}, SUBCIR - \phi_{SUB}$	-22 to +9	V	
Clock input voltage	$V\phi_1, V\phi_2, V\phi_3 - GND$	-15 to +16	V	
	$V\phi_1, V\phi_2, V\phi_3 - \phi_{SUB}$	to +10	V	
Voltage difference between vertical clock input pins		to +15	V	*1
Voltage difference between horizontal clock input pins		to +16	V	
$H\phi_1, H\phi_2 - V\phi_3$		-16 to +16	V	
$H\phi_1, H\phi_2 - GND$		-10 to +15	V	
$H\phi_1, H\phi_2 - \phi_{SUB}$		-55 to +10	V	
$V_L - \phi_{SUB}$		-65 to +0.3	V	
$V\phi_2, V\phi_3 - V_L$		-0.3 to +27.5	V	
RG - GND		-0.3 to +20.5	V	
$V\phi_1, H\phi_1, H\phi_2, GND - V_L$		-0.3 to +17.5	V	
Storage temperature		-30 to +80	°C	
Operating temperature		-10 to +60	°C	

\*1 +24V (Max.) when clock width < 10μs, clock duty factor < 0.1%.

**Bias Conditions**

Item	Symbol	Min.	Typ.	Max.	Unit	Remarks
Supply voltage	V <sub>DD</sub>	14.55	15.0	15.45	V	
Protective transistor bias	V <sub>L</sub>	*1				
Substrate clock	φ <sub>SUB</sub>	*2				

\*1 V<sub>L</sub> setting is the V<sub>VL</sub> voltage of the vertical transfer clock waveform, or the same power supply as the V<sub>L</sub> power supply for the V driver should be used.

\*2 Set SUBCIR pin to open when applying a DC bias to the substrate clock pin.

**DC Characteristics**

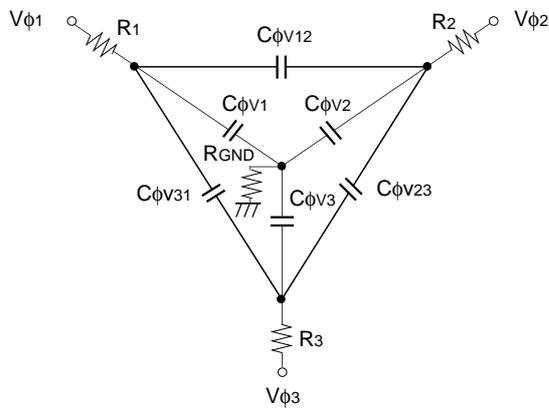
Item	Symbol	Min.	Typ.	Max.	Unit	Remarks
Supply current	I <sub>DD</sub>		6	8	mA	

**Clock Voltage Conditions**

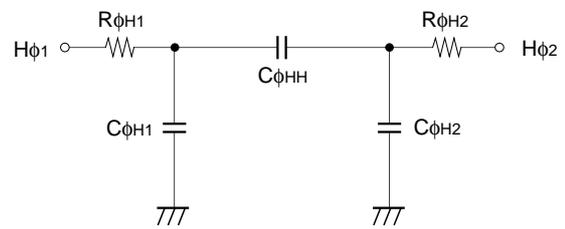
Item	Symbol	Min.	Typ.	Max.	Unit	Waveform diagram	Remarks
Readout clock voltage	V <sub>VT</sub>	14.55	15.0	15.45	V	1	
Vertical transfer clock voltage	V <sub>VH02</sub>	-0.05	0	0.05	V	2	V <sub>VH</sub> = V <sub>VH02</sub>
	V <sub>VH1</sub> , V <sub>VH2</sub> , V <sub>VH3</sub>	-0.2	0	0.05	V	2	
	V <sub>VL1</sub> , V <sub>VL2</sub> , V <sub>VL3</sub>	-8.0	-7.5	-7.0	V	2	V <sub>VL</sub> = (V <sub>VL1</sub> + V <sub>VL3</sub> )/2
	V <sub>φ1</sub> , V <sub>φ2</sub> , V <sub>φ3</sub>	6.8	7.5	8.05	V	2	
	V <sub>VL1</sub> - V <sub>VL3</sub>			0.1	V	2	
	V <sub>VHH</sub>			1.0	V	2	High-level coupling
	V <sub>VHL</sub>			2.3	V	2	High-level coupling
	V <sub>VLH</sub>			1.0	V	2	Low-level coupling
Horizontal transfer clock voltage	V <sub>φH</sub>	4.75	5.0	5.25	V	3	
	V <sub>H</sub>	-0.05	0	0.05	V	3	
Reset gate clock voltage	V <sub>φRG</sub>	4.5	5.0	5.5	V	4	Input through 0.01μF capacitance
	V <sub>RGLH</sub> - V <sub>RGLL</sub>			0.8	V	4	Low-level coupling
	V <sub>RGH</sub>	V <sub>DD</sub> +0.4	V <sub>DD</sub> +0.6	V <sub>DD</sub> +0.8	V	4	
Substrate clock voltage	V <sub>φSUB</sub>	21.5	22.5	23.5	V	5	

**Clock Equivalent Circuit Constant**

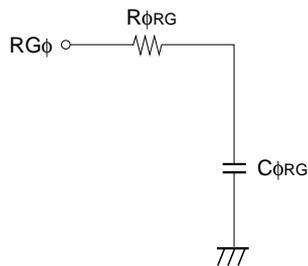
Item	Symbol	Min.	Typ.	Max.	Unit	Remarks
Capacitance between vertical transfer clock and GND	$C\phi V1$		560		pF	
	$C\phi V2$		470		pF	
	$C\phi V3$		1500		pF	
Capacitance between vertical transfer clocks	$C\phi V12$		1500		pF	
	$C\phi V23$		1500		pF	
	$C\phi V31$		1000		pF	
Capacitance between horizontal transfer clock and GND	$C\phi H1, C\phi H2$		43		pF	
Capacitance between horizontal transfer clocks	$C\phi HH$		39		pF	
Capacitance between reset gate clock and GND	$C\phi RG$		5		pF	
Capacitance between substrate clock and GND	$C\phi SUB$		570		pF	
Vertical transfer clock series resistor	$R1, R2$		20		$\Omega$	
	$R3$		56		$\Omega$	
Vertical transfer clock ground resistor	$R_{GND}$		43		$\Omega$	
Horizontal transfer clock series resistor	$R\phi H1, R\phi H2$		10		$\Omega$	
Reset gate clock series resistor	$R\phi RG$		39		$\Omega$	



**Vertical transfer clock equivalent circuit**



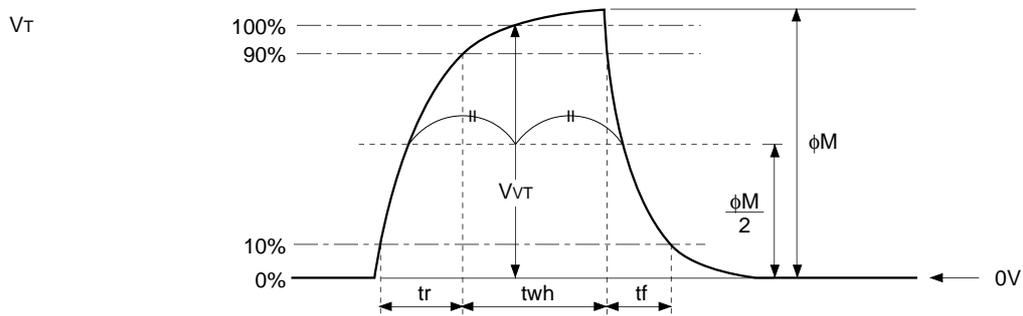
**Horizontal transfer clock equivalent circuit**



**Reset gate clock equivalent circuit**

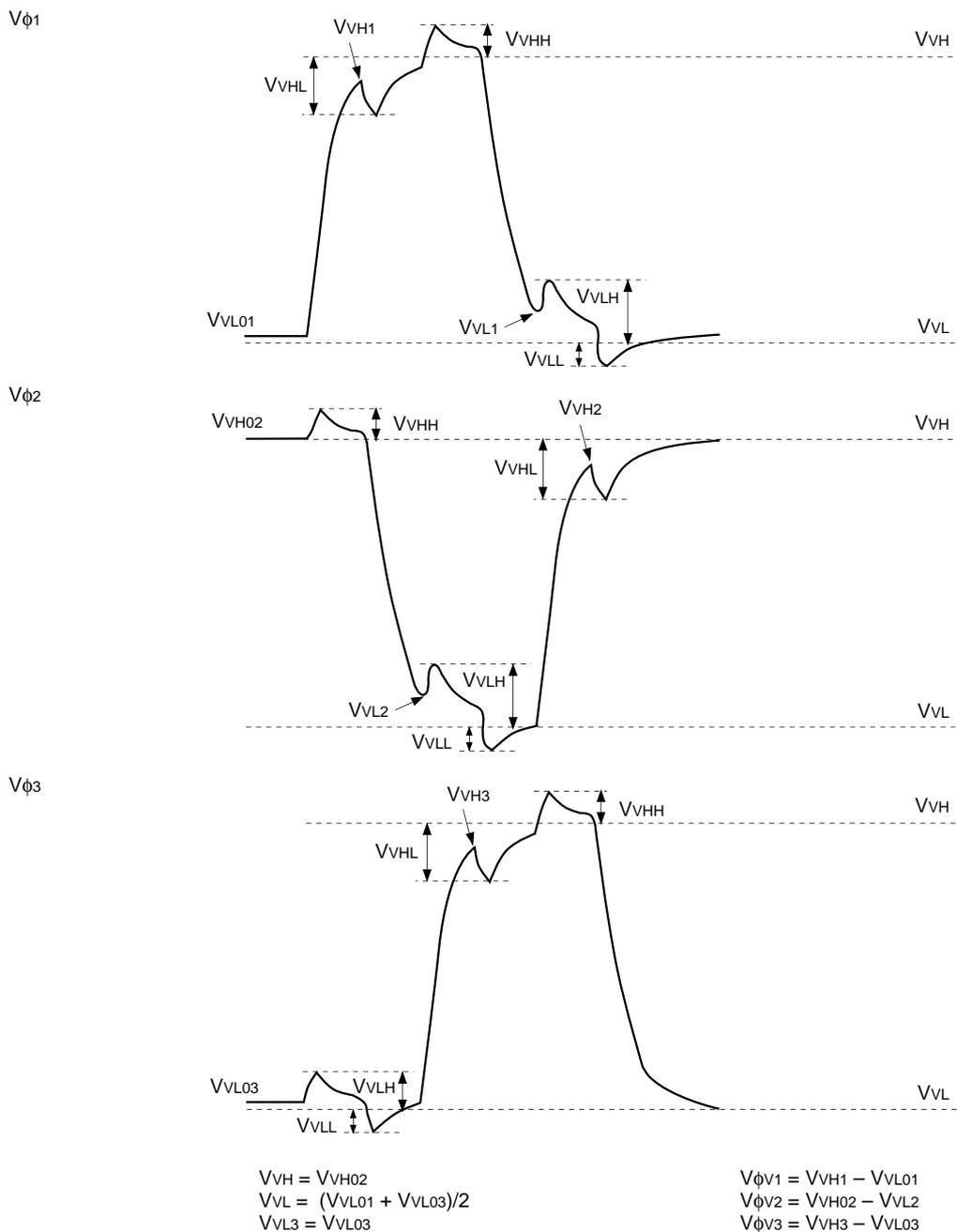
Drive Clock Waveform Conditions

(1) Readout clock waveform

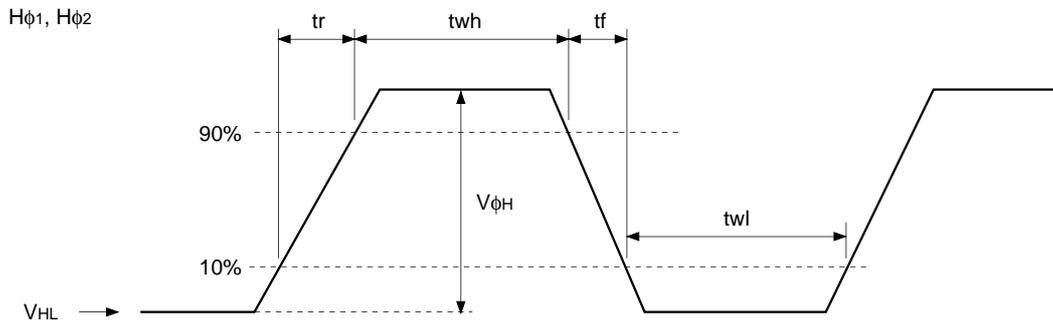


Note) Readout clock is used by composing vertical transfer clocks \$V\phi\_2\$ and \$V\phi\_3\$.

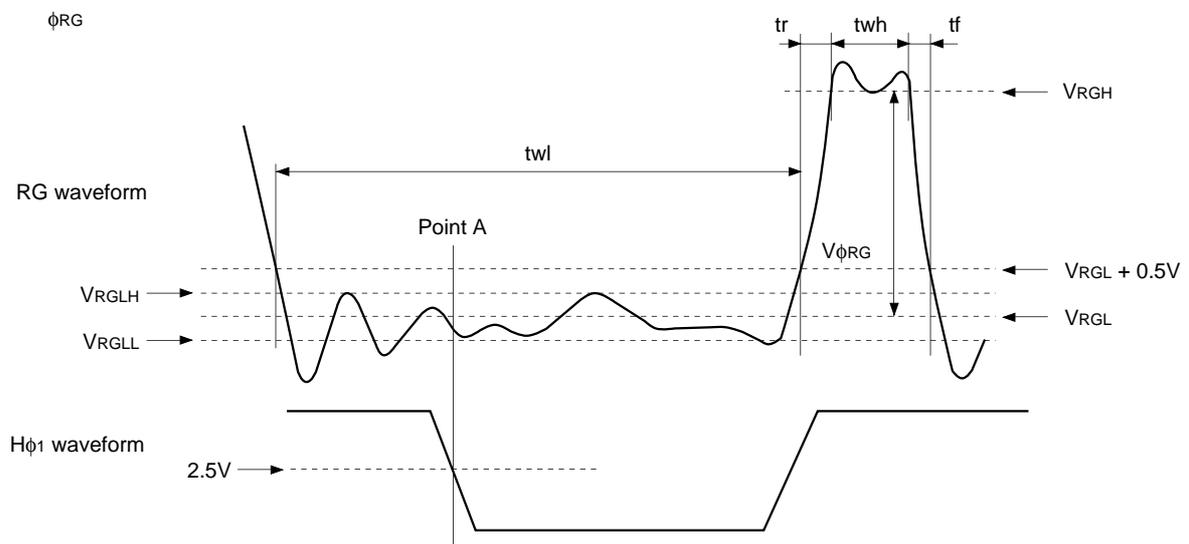
(2) Vertical transfer clock waveform



**(3) Horizontal transfer clock waveform**



**(4) Reset gate clock waveform**



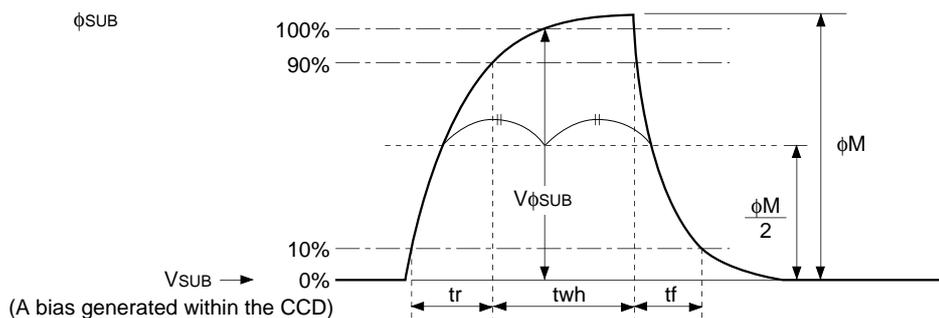
$V_{RGLH}$  is the maximum value and  $V_{RGLL}$  is the minimum value of the coupling waveform during the period from Point A in the above diagram until the rising edge of RG. In addition,  $V_{RGL}$  is the average value of  $V_{RGLH}$  and  $V_{RGLL}$ .

$$V_{RGL} = (V_{RGLH} + V_{RGLL})/2$$

Assuming  $V_{RGH}$  is the minimum value during the interval  $t_{wh}$ , then:

$$V_{\phi RG} = V_{RGH} - V_{RGL}$$

**(5) Substrate clock waveform**



## Clock Switching Characteristics

Item	Symbol	twh			twl			tr			tf			Unit	Remarks	
		Min.	Typ.	Max.	Min.	Typ.	Max.	Min.	Typ.	Max.	Min.	Typ.	Max.			
Readout clock	$V_T$	2.3	2.5						0.5			0.5		$\mu\text{s}$	During readout	
Vertical transfer clock	$V_{\phi 1}, V_{\phi 2}, V_{\phi 3}$										15		350	ns	*1	
Horizontal transfer clock	During imaging	$H_{\phi 1}$	24	30		25	31.5			10	17.5		10	17.5	ns	*2
		$H_{\phi 2}$	26.5	31.5		25	30			10	15		10	15		
	During parallel-serial conversion	$H_{\phi 1}$								0.01			0.01		$\mu\text{s}$	
		$H_{\phi 2}$								0.01			0.01			
Reset gate clock	$\phi_{RG}$	11	13			62.5			3			3		ns		
Substrate clock	$\phi_{SUB}$	1.5	1.8							0.5			0.5	$\mu\text{s}$	During drain charge	

\*1 When vertical transfer clock driver CXD1267AN is used.

\*2  $t_f \geq t_r - 2\text{ns}$ , and the cross-point voltage ( $V_{CR}$ ) for the  $H_{\phi 1}$  rising side of the  $H_{\phi 1}$  and  $H_{\phi 2}$  waveforms must be at least 2.5V.

Item	Symbol	two			Unit	Remarks
		Min.	Typ.	Max.		
Horizontal transfer clock	$H_{\phi 1}, H_{\phi 2}$	21.5	25.5		ns	*3

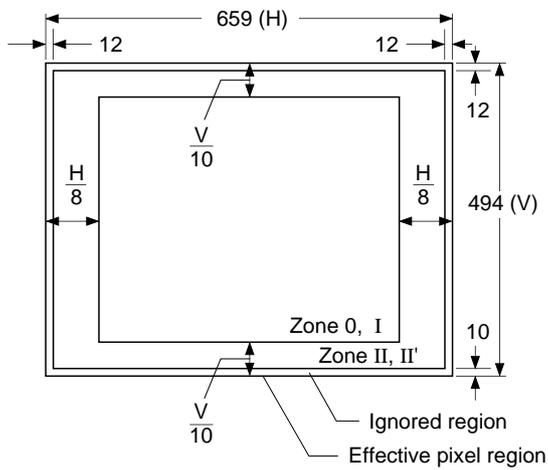
\*3 The overlap period for twh and twl of horizontal transfer clocks  $H_{\phi 1}$  and  $H_{\phi 2}$  is two.

Image Sensor Characteristics

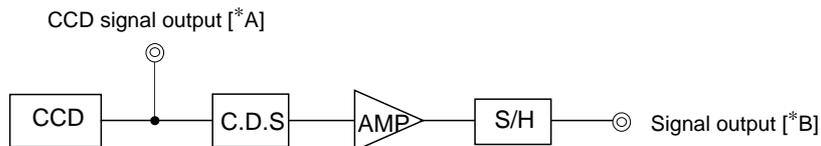
(Ta = 25°C)

Item	Symbol	Min.	Typ.	Max.	Unit	Measurement method	Remarks
Sensitivity	S	540	700		mV	1	
Saturation signal	Vsat	500			mV	2	Ta = 60°C
Smear	Sm		0.005	0.015	%	3	
Video signal shading	SH			20	%	4	Zone 0 and I
				25	%	4	Zone 0 to II'
Dark signal	Vdt			4	mV	5	Ta = 60°C
Dark signal shading	$\Delta Vdt$			1	mV	6	Ta = 60°C
Lag	Lag			0.5	%	7	

Zone Definition of Video Signal shading



Measurement System



Note) Adjust the amplifier gain so that the gain between [\*A] and [\*B] equals 1.

## Image Sensor Characteristics Measurement Method

### ◎ Measurement conditions

- 1) In the following measurements, the device drive conditions are at the typical values of the bias and clock voltage conditions.
- 2) In the following measurements, spot blemishes are excluded and, unless otherwise specified, the optical black level (OB) is used as the reference for the signal output, which is taken as the value measured at point [\*B] of the measurement system.

### ◎ Definition of standard imaging conditions

- 1) Standard imaging condition I:  
Use a pattern box (luminance : 706cd/m<sup>2</sup>, color temperature of 3200K halogen source) as a subject. (pattern for evaluation is not applicable.) Use a testing standard lens with CM500S (t = 1.0mm) as an IR cut filter and image at F8. The luminous intensity to the sensor receiving surface at this point is defined as the standard sensitivity testing luminous intensity.
- 2) Standard imaging condition II:  
Image a light source (color temperature of 3200K) with a uniformity of brightness within 2% at all angles. Use a testing standard lens with CM500S (t = 1.0mm) as an IR cut filter. The luminous intensity is adjusted to the value indicated in each testing item by the lens diaphragm.

#### 1. Sensitivity

Set to standard imaging condition I. After selecting the electronic shutter mode with a shutter speed of 1/250s, measure the signal output (Vs) at the center of the screen, and substitute the value into the following formula.

$$S = V_s \times \frac{250}{30} \text{ [mV]}$$

#### 2. Saturation signal

Set to standard imaging condition II. After adjusting the luminous intensity to 10 times the intensity with the average value of the signal output, 150mV, measure the minimum value of the signal output.

#### 3. Smear

Set to standard imaging condition II. With the lens diaphragm at F5.6 to F8, first adjust the luminous intensity to 500 times the intensity with the average value of the signal output, 150mV. Then after the readout clock is stopped and the charge drain is executed by the electronic shutter at the respective H blankings, measure the maximum value (Vsm [mV]) of the signal output and substitute the value into the following formula.

$$S_m = \frac{V_{sm}}{150} \times \frac{1}{500} \times \frac{1}{10} \times 100 \text{ [%]} \text{ (1/10V method conversion value)}$$

#### 4. Video signal shading

Set to standard imaging condition II. With the lens diaphragm at F5.6 to F8, adjust the luminous intensity so that the average value of the signal output is 150mV. Then measure the maximum (Vmax [mV]) and minimum (Vmin [mV]) values of the signal output and substitute the values into the following formula.

$$SH = (V_{max} - V_{min})/150 \times 100 \text{ [%]}$$

#### 5. Dark signal

Measure the average value of the signal output (Vdt [mV]) with the device ambient temperature 60°C and the device in the light-obstructed state, using the horizontal idle transfer level as a reference.

6. Dark signal shading

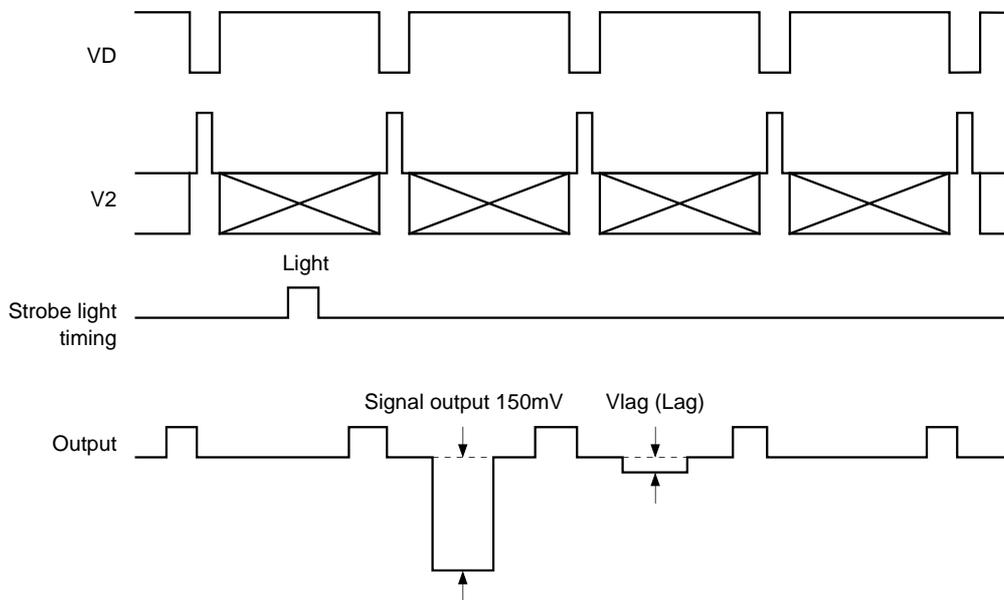
After measuring 5, measure the maximum (Vdmax [mV]) and minimum (Vdmin [mV]) values of the dark signal output and substitute the values into the following formula.

$$\Delta V_{dt} = V_{dmax} - V_{dmin} \text{ [mV]}$$

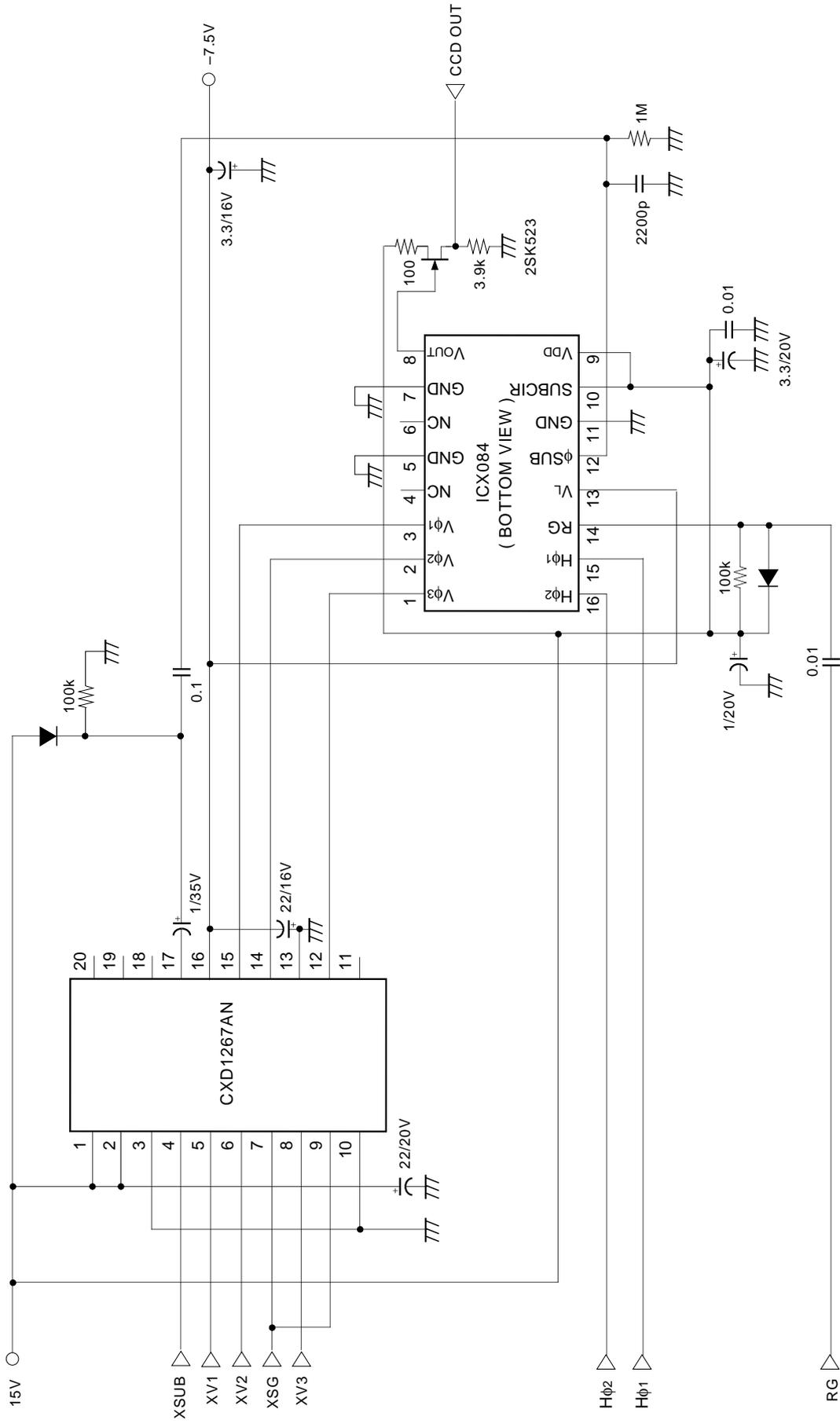
7. Lag

Adjust the signal output value generated by strobe light to 150mV. After setting the strobe light so that it strobes with the following timing, measure the residual signal (Vlag). Substitute the value into the following formula.

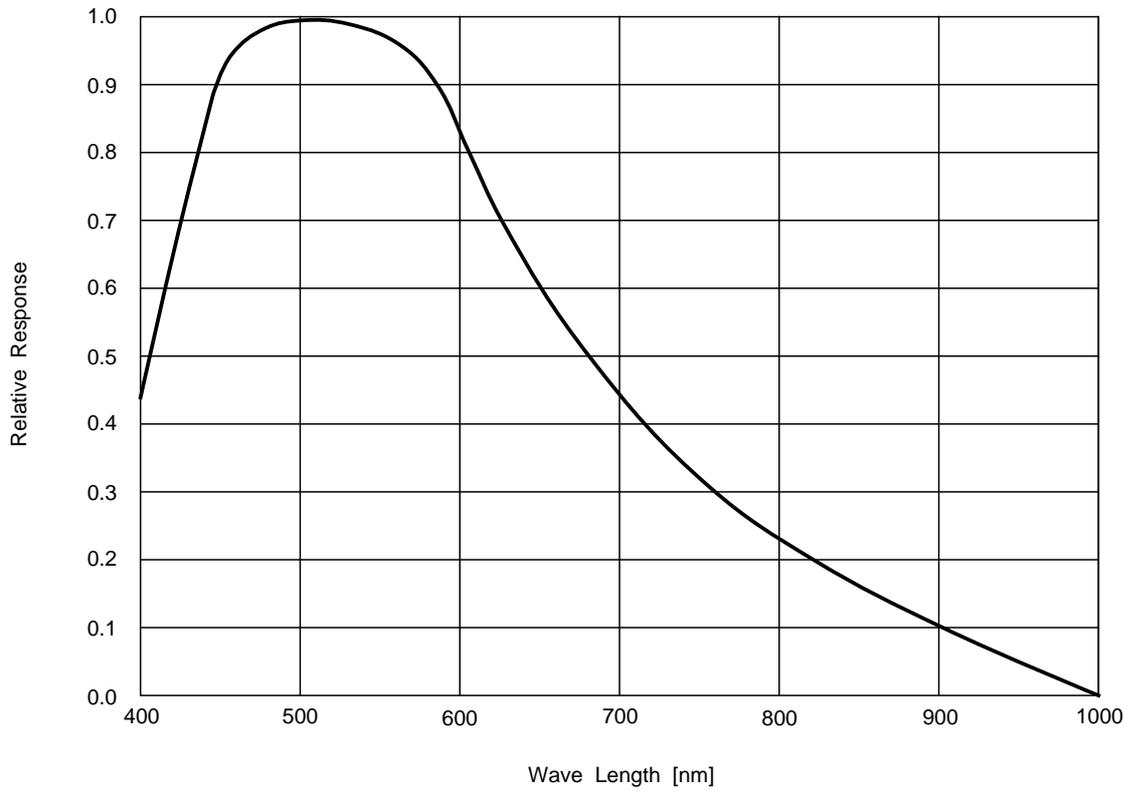
$$\text{Lag} = (V_{lag}/150) \times 100 \text{ [%]}$$



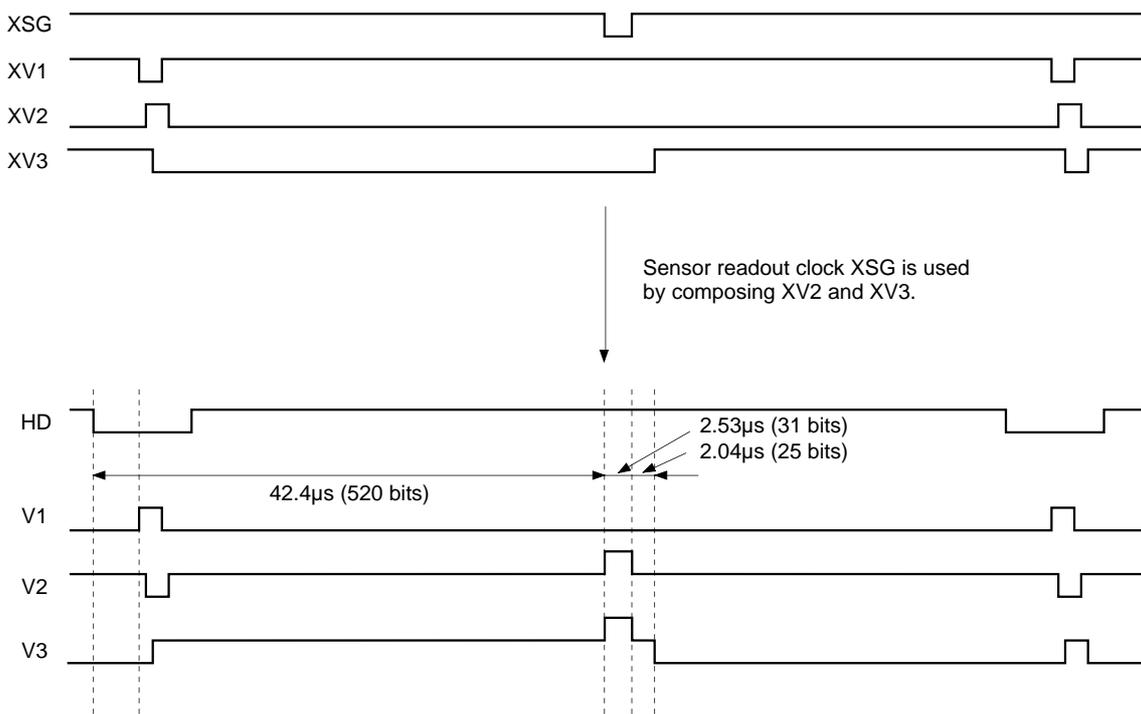
Drive Circuit



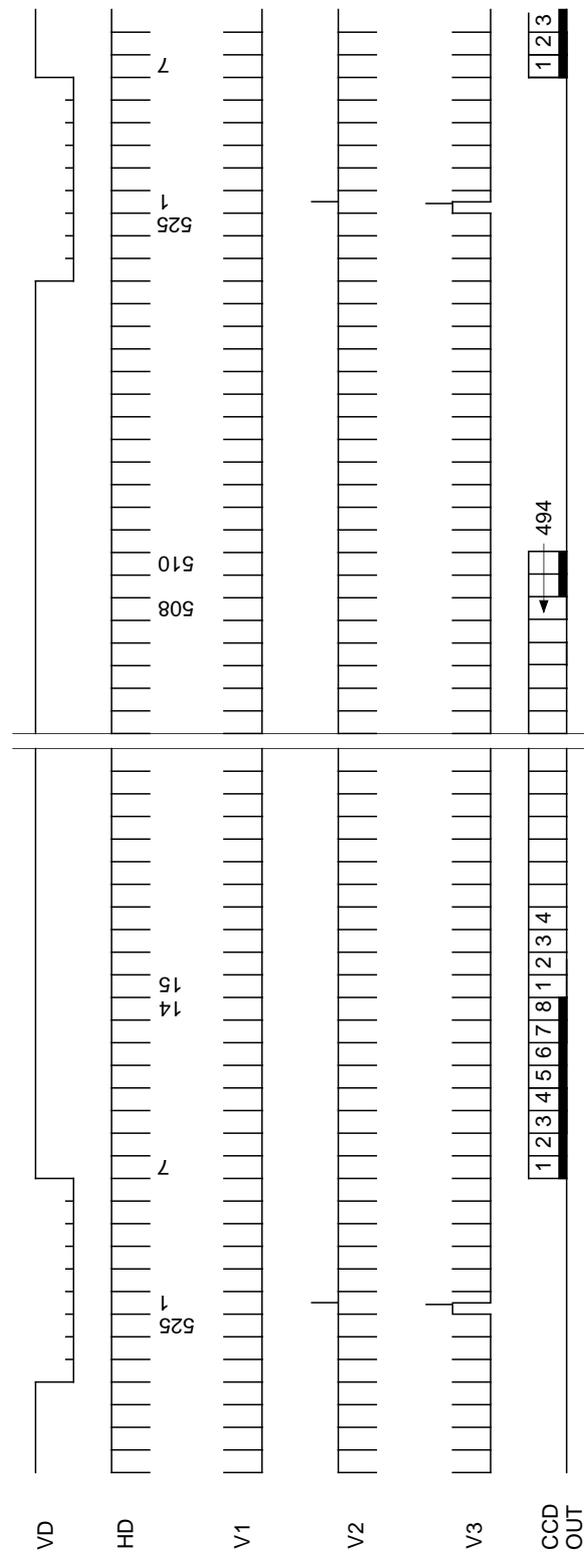
**Spectral Sensitivity Characteristics** (Includes lens characteristics, excludes light source characteristics)



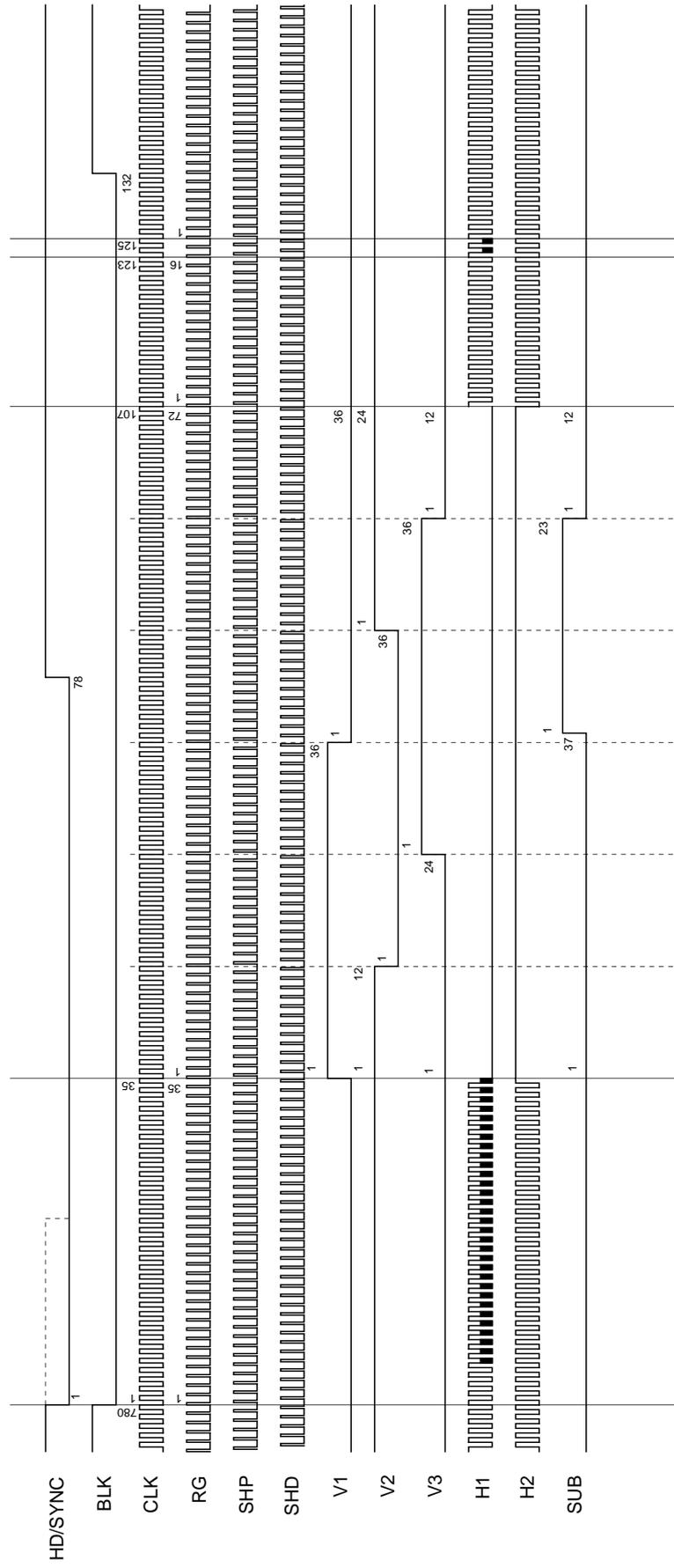
**Sensor Readout Clock Timing Chart**



Drive Timing Chart (Vertical Sync)



Drive Timing Chart (Horizontal Sync)



## Notes on Handling

### 1) Static charge prevention

CCD image sensors are easily damaged by static discharge.

Before handling be sure to take the following protective measures.

- a) Either handle bare handed or use non-chargeable gloves, clothes or material. Also use conductive shoes.
- b) When handling directly use an earth band.
- c) Install a conductive mat on the floor or working table to prevent the generation of static electricity.
- d) Ionized air is recommended for discharge when handling CCD image sensor.
- e) For the shipment of mounted substrates, use boxes treated for the prevention of static charges.

### 2) Soldering

a) Make sure the package temperature does not exceed 80°C.

b) Solder dipping in a mounting furnace causes damage to the glass and other defects. Use a ground 30W soldering iron and solder each pin in less than 2 seconds. For repairs and remount, cool sufficiently.

c) To dismount an image sensor, do not use a solder suction equipment. When using an electric desoldering tool, use a thermal controller of the zero cross On/Off type and connect it to ground.

### 3) Dust and dirt protection

Image sensors are packed and delivered by taking care of protecting its glass plates from harmful dust and dirt. Clean glass plates with the following operation as required, and use them.

a) Operate in clean environments (around class 1000 is appropriate).

b) Do not either touch glass plates by hand or have any object come in contact with glass surfaces.

Should dirt stick to a glass surface, blow it off with an air blower. (For dirt stuck through static electricity ionized air is recommended.)

c) Clean with a cotton bud and ethyl alcohol if the grease stained. Be careful not to scratch the glass.

d) Keep in a case to protect from dust and dirt. To prevent dew condensation, preheat or precool when moving to a room with great temperature differences.

e) When a protective tape is applied before shipping, just before use remove the tape applied for electrostatic protection. Do not reuse the tape.

4) Do not expose to strong light (sun rays) for long periods. For continuous using under cruel condition exceeding the normal using condition, consult our company.

5) Exposure to high temperature or humidity will affect the characteristics. Accordingly avoid storage or usage in such conditions.

6) CCD image sensors are precise optical equipment that should not be subject to too much mechanical shocks.

